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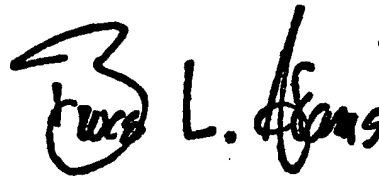
JAPG Rec'd PCT/PTO 18 AUG 2006

Attorney Docket No.	S005-5850 (PCT)
First Inventor	Takashi OGAWA
Title	SEMICONDUCTOR INSPECTION METHOD AND SYSTEM THERE- FOR
Express Mail Label No.	EV. 666 011 623 US

CLAIM FOR FOREIGN PRIORITY

Applicant(s) claim(s) the benefit of priority of the following application(s):

JAPANESE PATENT APPLN. NO. 2004-050296
FILED FEBRUARY 25, 2004



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